



Mechanical Data	Notes
Dice size	Ax:380um,Ay:380um
Wafer size	4" (Gross die:40,320pcs/Good die>38,304pcs)
Chip Thickness	138um±12um
Scribe line width	60um
Top metal	Al/Au/Ag
Back side metal	Al/Au/Ag/Sn

Parameter	Symbol	Conditions	Value	Unit
Reverse stand-off voltage	VRWM		3.3	V
Peak pulse power	PPP	Tp=8/20us	250*	W
Peak pulse current	IPP	Tp=8/20us	15.0*	A
Electrostatic discharge	VESD	IEC61000-4-2 Level-4	± 10(Contact) ±25(Air)	KV
Max.junction temp.	Tj		150	°C

Characteristics TA=25°C

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Breakdown voltage	VBR	IT=1mA	3.5			V
Reverse leakage current	IR	V=±3.0V		0.05	0.9	uA
Snap-Back Voltage	Vsb	Isb=50mA	3.3		5.3	V
Clamping Voltage	Vc	IPP=1.0A IPP=15.0A			5.5* 10.0*	V
Diode capacitance	Cj	VR=0V f=1MHZ		25.0		pf

Notes:

- (1)sampling testing:no bad dice inking/guaranteed good die >95%
- (2)Testing follow customer
- (3) $T_j = T_a + R_{th}(j-a) * (P_f + P_r)$, where $R_{th}(j-a)$ -thermal resistance, P_f -forward power dissipation, P_r -revers power dissipation
- (4)**For device testing